

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KAWAGUCHI ET AL.	
		Examiner Sue Liu	Art Unit 1639	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0051973 A1	05-2002	DELENSTARR et al.	435/6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Dudley et al., Measuring absolute expression with microarrays with a calibrated reference sample and an extended signal intensity range. PNAS. Vol. 99: 7554-7559.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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